

ASA-1236

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Yasumaro Komiya, et al  
Serial No.: Not Yet Assigned  
Filed: On Even Date  
For: DEFECT ANALYSIS APPARATUS, SYSTEM AND METHOD FOR  
SEMICONDUCTOR INTEGRATED CIRCUIT

**INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 CFR 1.97 & 1.98**

April 29, 2005

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application, applicants are submitting herewith copies of any foreign or publication (i.e. articles) documents. Applicants also submit that copies of any U.S. Patents are not being submitted since these documents can be easily obtained by the United States Patent and Trademark Office as listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted with the new application.

Although some of the documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR 1.98 (a) (3) for a concise explanation of the relevance is satisfied by the attached English language abstracts and/or the discussion of some of the documents in the specification.

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Mattingly, Stanger , Malur & Brundidge, P.C. Deposit Account No. 50-1417 (Case: ASA-1236), and please credit any excess fees to such deposit account.

Respectfully submitted,

Mattingly, Stanger & Malur, Brundidge, P.C.

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Carl I. Brundidge  
Registration No. 29,621

CIB/nac

Attachments

Sheet 1 of 1

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO.  ASA-1236	SERIAL NO.  10/533127
	INFORMATION DISCLOSURE STATEMENT BY APPLICANT  (Use several sheets if necessary)	APPLICANT Yasumaro KOMIYA, et al	
		FILING DATE April 29, 2005	GROUP

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
AA	5514971A	5/1996				
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Abstract	
						Yes	No
AM	2001-166012A	2001	JP			X	
AN	9-92701	1997	JP			X	
AO	1-277781	1989	JP			X	
AP	10-10208	1998	JP			X	
AQ	2001-141776						
AR							
AS							
AT							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AU	
AV	
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Examiner	Date Considered